



Contribution ID: 213

Type: **Poster**

## Full-Array Noise Performance of Deployment-Grade SuperSpec mm-wave On-Chip Spectrometers

*Tuesday, July 23, 2019 6:45 PM (15 minutes)*

SuperSpec is an on-chip filter-bank spectrometer designed for wideband moderate-resolution spectroscopy at millimeter and submillimeter wavelengths, employing TiN kinetic inductance detectors. SuperSpec technology will enable integral-field-unit spectrometers suitable for high-redshift line intensity mapping or multi-object spectrographs. We plan to deploy a demonstration instrument to the Large Millimeter Telescope (LMT) in mid-2019, featuring six independent single-polarization SuperSpec chips and covering 190-310 GHz with 100 channels each.

In previous results, we have demonstrated noise performance for individual detectors suitable for photon noise limited observations at excellent mm-wave observing sites. In these proceedings, we present the complete system-level noise performance of deployment-grade devices that we will use at the LMT, measured through a ROACH-based readout system. Array statistics such as NEP, responsivity, and low-frequency noise performance will be shown for all channels and compared to the expected observing conditions and planned scan strategy at the LMT.

### Less than 5 years of experience since completion of Ph.D

Y

### Student (Ph.D., M.Sc. or B.Sc.)

N

**Primary authors:** Dr KARKARE, Kirit (University of Chicago); BARRY, Peter (Argonne National Laboratory); Dr BRADFORD, Matt (JPL); CHAPMAN, Scott (Dalhousie University); GLENN, Jason (University of Colorado - Boulder); HAILEY-DUNSHEATH, Steven (California Institute of Technology); JANSSEN, Reinier (Jet Propulsion Laboratory); LEDUC, Henry G. (Jet Propulsion Laboratory); MAUSKOPF, Phillip (Arizona State University); MCGEEHAN, Ryan (University of Chicago); SHIROKOFF, Erik (University of Chicago); WHEELER, Jordan (University of Colorado - Boulder); ZMUIDZINAS, Jonas (California Institute of Technology)

**Presenter:** Dr KARKARE, Kirit (University of Chicago)

**Session Classification:** Poster session

**Track Classification:** Detector readout, signal processing, and related technologies